

Notice of References Cited	Application/Control No.	Applicant(s)/Patent Under Reexamination	
	10/646,892	MAEDA, HITOSHI	
	Examiner David A. Rogers	Art Unit 2856	Page 1 of 1

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-5,166,520	11-1992	Prater et al.	250/306
B	US-5,461,605	10-1995	Takimoto et al.	369/126
C	US-6,461,907	10-2002	Imai, Kiyotaka	438/217
D	US-5,469,733	11-1995	Yasue et al.	73/105
E	US-5,581,083	12-1996	Majumdar et al.	250/306
F	US-5,723,775	03-1998	Watanabe et al.	73/105
G	US-5,892,223	04-1999	Karpov et al.	250/306
H	US-6,051,825	04-2000	Lindsay et al.	250/201.3
I	US-6,328,902	12-2001	Hantschel et al.	216/2
J	US-2002/0079445	06-2002	Hantschel et al.	250/306
K	US-2002/0178799	12-2002	Kitazawa et al.	73/105
L	US-2002/0178800	12-2002	Hasegawa et al.	73/105
M	US-2002/0178801	12-2002	Takahashi et al.	73/105

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)	
U	Matey et al., "Scanning Capacitance Microscopy", 01 March 1995, Journal of Applied Physics, Vol. 5, No. 5, pages 1437-1444.	
V	Steeves et al., "Ultrafast Scanning Tunneling Microscopy", 2002, pages 1-51.	
W		
X		

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.